CLAIM AMENDMENTS

- 1. (Currently Amended) A thermal type infrared detector comprising: a substrate;
- a temperature sensor of which electric having electrical characteristics are changed that change in accordance with response to a temperature change caused by infrared absorption of infrared rays;

heat-insulating supporting legs for supporting and thermally insulating said temperature sensor in a heat-insulating manner and serving as including signal lines for reading out electrical signals from said temperature sensor; and

an infrared absorption layer having in thermal contact with said temperature sensor; wherein each of said temperature sensor, said heat-insulating supporting legs, and said infrared absorption layer is formed in a respective different planes that plane and the planes are spatially apart separated from each other.

- 2. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said temperature sensor and said infrared absorption layer are formed in a region that overlaps overlap said heat-insulating supporting legs when seen from the direction of viewed along incident infrared rays.
- 3. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said temperature sensor and said infrared absorption layer are formed in a region that cover substantially evers the entire surface all of said heat-insulating supporting legs when seen from the direction of viewed along incident infrared rays
- 4. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said infrared absorption layer, said heat-insulating supporting legs, and said temperature sensor are laminated sequentially when seen from the direction of viewed along incident infrared rays.
- 5. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said temperature sensor comprises a diode or a plurality of diodes that are serially connected.
- 6. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said temperature sensor comprises a transistor.

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- 7. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said substrate includes a mono-crystalline silicon layer formed on an insulating thin film and wherein said temperature sensor is formed in said mono-crystalline layer.
- 8. (Currently Amended) The thermal type infrared detector according to claim 1, wherein the portion of said substrate under opposite said temperature sensor is removed thinner than elsewhere.
- 9. (Currently Amended) The thermal type infrared detector according to claim 1, wherein said temperature sensor comprises a bolometer film.
- 10. (Currently Amended) A method for manufacturing a thermal type infrared detector comprising:

forming a temperature sensor on a substrate, the electric said temperature sensor having electrical characteristics of said temperature sensor being changed changing in accordance with a change in temperature ehange;

forming a first sacrifice sacrificial layer that covers covering said temperature sensor and partially contacts with contacting said substrate;

removing a portion of said first sacrifice sacrificial layer to expose a portion of said temperature sensor;

forming a wiring layer on said first sacrifice sacrificial layer so that, said wiring layer being electrically connected to said temperature sensor at a portion exposed from not covered by said first sacrifice sacrificial layer;

forming a second sacrifice sacrificial layer that covers covering said wiring layer and partially contacts with contacting part of said first sacrifice sacrificial layer;

forming via holes by removing a part of said first and second sacrifice sacrificial layers;

forming an infrared absorbing layer on said second sacrifice sacrificial layer so that said infrared absorbing layer contacts with said temperature sensor via through said via holes either directly or interposing a with an insulating layer in between interposed;

removing said second sacrifice layer, said first sacrifice layer, and the <u>a</u> portion of said substrate under opposite said temperature sensor.

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11. (Currently Amended) A method for manufacturing a thermal type infrared detector comprising:

forming a first sacrifice sacrificial layer on a substrate;

forming a temperature sensor on said first sacrifice sacrificial layer, the electric characteristics of said temperature sensor being changed having electrical characteristics that change in accordance with changes in temperature on a substrate;

forming a second sacrifice sacrificial layer that covers covering said temperature sensor and partially contacts with contacting said first sacrifice sacrificial layer;

removing a portion of said second sacrifice sacrificial layer to expose a portion of said temperature sensor;

forming a wiring layer on said second sacrifice sacrificial layer so that said wiring layer electrically connected to said temperature sensor at a portion exposed from not covered by said second sacrifice sacrificial layer;

forming a third sacrifice sacrificial layer that covers covering said wiring layer and partially contacts with contacting part of said second sacrifice layer;

forming via holes by removing a part of said third and second sacrifice sacrificial layers;

forming an infrared absorbing layer on said third sacrifice sacrificial layer so that said infrared absorbing layer contacts with and contacting said temperature sensor via through said via holes either directly or interposing a with an insulating layer in between interposed;

removing said third sacrifice sacrificial layer, said second sacrifice sacrificial layer, and said first sacrifice sacrificial layer.

- 12. (Currently Amended) An infrared focal plane array comprising a plurality of thermal type infrared detectors according to claim 1, wherein said infrared detectors are arranged in a two-dimensional manner array.
- 13. (Currently Amended) An infrared focal plane array comprising a plurality of thermal type infrared detectors according to claim 5, wherein said infrared detectors are arranged in a two-dimensional manner and applied array, a forward bias voltage to flow is applied so a constant current flows, and wherein an the end-to-end voltage generated by incident infrared rays in each of said infrared detectors are is read out as an image signal.
- 14. (Currently Amended) The infrared focal plane array according to claim 13, further comprising a reference temperature sensor and differential input circuits to which both

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signals from both of said infrared detectors and said reference temperature sensor enter are applied, wherein said reference temperature sensor has substantially the same a temperature-voltage characteristic substantially the same as those of said infrared detectors and is substantially non-sensitive insensitive to the incident infrared rays.